

Photoemission study of TiO₂/VO₂ interfaces

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Introduction

Metal-insulator transition has been extensively studied because of its fundamental interest as well as its close relationship to remarkable phenomena such as high-temperature superconductivity in cuprates and colossal magnetoresistance in manganites [1]. Recently, high quality interfaces between transition metal oxides have become available due to the development of sample preparation technique. Particularly, interfaces between the band insulator SrTiO₃ (d⁰) and the Mott insulator LaSrTiO₃ (d¹) have attracted interest because of its metallic behavior [2-5]. In the present work, we have performed photoemission spectroscopy (PES) measurements of interfaces between another d⁰ band insulator TiO₂ and d¹ Mott insulator VO₂.

Experiment

VO₂/TiO₂ thin films were prepared using pulse laser deposition (PLD) technique. V₂O₃ pellet was used as a target. During the deposition, the substrate temperature was kept at 733 K and oxygen pressure was maintained at 1.0 Pa. The film thickness was about 10 nm-15 nm. TiO₂ capped samples were prepared as follows. The Rutile-type TiO₂ (r-TiO₂) deposited 673 K on the VO₂ thin film, while amorphous TiO₂ (a-TiO₂) was deposited TiO₂ at room temperature. Photoemission measurements were performed at BL-2C of Photon Factory. PES spectra were measured using a Scienta SES-100 analyzer.

Results and Discussion

PES spectra in the V 3d band region of VO₂, a-TiO₂/VO₂, r-TiO₂/VO₂ are shown in Fig. 1. All the spectra showed both coherent and incoherent parts. Incoherent part was observed most strongly in the r-TiO₂/VO₂. This may be caused by the difference in the sample preparation process. In the r-TiO₂/VO₂ sample, Ti and V atoms may be interdiffused at the interface and the interface region may behave like Ti-doped VO₂ which become insulating as the Ti concentration increases. The temperature dependence of the V 3d band of a-TiO₂/VO₂, r-TiO₂/VO₂ are shown in Fig. 2. In both samples, metallic states were not observed in the interface between insulating VO₂ and insulating TiO₂ at low temperature, in contrast to the case of SrTiO₃-LaTiO₃ interface.

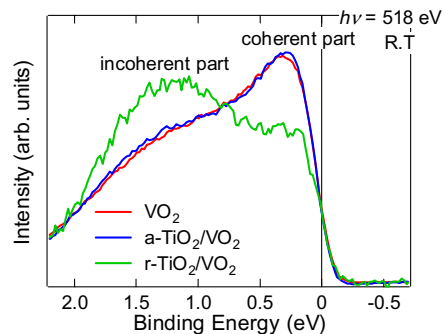


Fig. 1: V 3d band of VO₂, a-TiO₂/VO₂, r-TiO₂/VO₂.

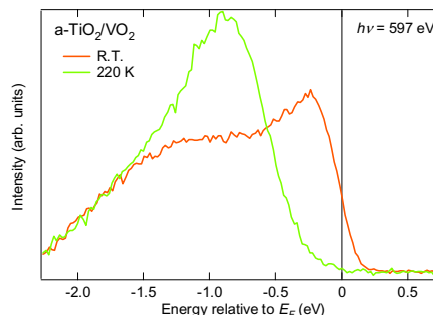


Fig. 2: Temperature-dependent photoemission spectra a-TiO₂/VO₂.

References

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